

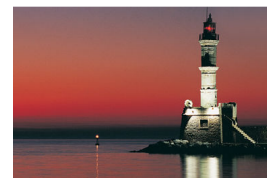


# CALL FOR PAPERS

## 19<sup>th</sup> IEEE International On-Line Testing Symposium

Minoa Palace Resort & Spa, Chania, Crete, Greece, July 8-10, 2013

<http://tima.imag.fr/conferences/iolts>



Issues related to on-line testing are increasingly important in modern electronic systems. In particular, the huge complexity of electronic systems has led to growth in reliability needs in several application domains as well as pressure for low cost products. There is a corresponding increasing demand for cost-effective on-line testing techniques. These needs have increased dramatically with the introduction of very deep submicron and nanometer technologies which adversely impact noise margins, process, voltage and temperature variations, aging and wear-out and make integrating on-line testing and fault tolerance mandatory in many modern ICs. The International On-Line Testing Symposium (IOLTS) is an established forum for presenting novel ideas and experimental data on these areas. The symposium also emphasizes on-line testing in the continuous operation of large applications such as wired, cellular and satellite telecommunication, as well as in secure chips. The Symposium is sponsored by the IEEE Council on Electronic Design Automation (CEDA) and the 2013 edition is organized by the IEEE Computer Society Test Technology Technical Council, the University of Athens, and the TIMA Laboratory.

### The topics of interest include (but are not limited to) the following ones:

- Reliability issues in nanometer technologies
- Radiation effects
- Design for reliability
- Design for variability
- On-line power monitoring and control
- On-line current, temperature, etc, monitoring
- Secure circuit design
- Fault-based attacks and counter measures
- Self-checking circuits and coding theory
- On-line testing of analog and mixed signal circuits
- On-line testing in industry, automotive, railway, avionics, space
- On-line testing in the continuous operation of large systems
- Field diagnosis, maintainability and reconfiguration
- Fault-tolerant and fail-safe systems
- Dependability evaluation
- Dependable systems design
- On-line and off-line built-in self-test
- Synthesis of on-line testable circuits

**Submissions:** The IOLTS Committee invites authors to submit papers in the above or related technical areas. Accepted papers and posters will be included in formal Proceedings to be published by the IEEE. Papers must be submitted electronically following the instructions provided at the symposium web site. Papers should be in the standard IEEE conferences double-column format. If accepted, regular papers should be allowed six pages in the IEEE Proceedings of the Symposium.

### Please observe the following key dates:

Submission deadline: **March 1, 2013** – Notification of acceptance: **April 15, 2013** – Camera-ready papers due: **May 15, 2013**

#### Submission Information

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**About the location:** IOLTS 2013 will be held in Chania, a blessed place with a mild climate, countless beauties and all kinds of attractions. Wandering around the Old Town's maze-like alleys with the beautiful Venetian mansions, the fountains and the elaborate churches will help you discover well-preserved historical monuments. Get familiar by visiting its museums and admiring the different architectural styles presenting the historical route of the town. The entire region is also breathtaking. The sandy beaches, the mountain villages, the seaside hamlets, the pure nature, the Byzantine monasteries spread along the inland, all create a fantastic background. You will have the chance to hike impressive gorges, such as the Gorge of Samaria, and see rare flora and fauna.

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For all updated information concerning IOLTS 2013, please visit the IOLTS web site: <http://tima.imag.fr/conferences/iolts>



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